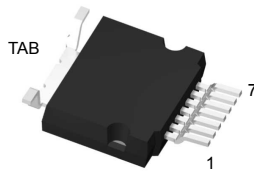
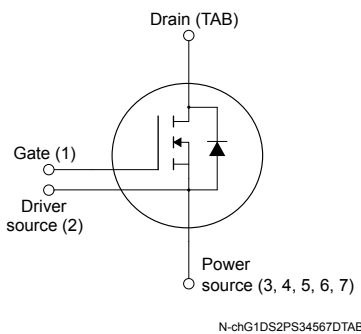


Automotive-grade N-channel 650 V, 38 mΩ typ., 51 A MDmesh DM9 Power MOSFET in an HU3PAK package



HU3PAK



Product status link


[STHU65N050DM9AG](#)

Product summary

| | |
|------------|-----------------|
| Order code | STHU65N050DM9AG |
| Marking | 65A050DM9 |
| Package | HU3PAK |
| Packing | Tape and reel |

Features

| Order code | V _{DS} | R _{DS(on)} max. | I _D |
|-----------------|-----------------|--------------------------|----------------|
| STHU65N050DM9AG | 650 V | 50 mΩ | 51 A |

- AEC-Q101 qualified 
- Fast-recovery body diode
- Very low FOM (R_{DS(on)}·Q_g)
- Low gate charge, input capacitance and resistance
- 100% avalanche tested
- Extremely high dv/dt ruggednes
- Excellent switching performance thanks to the extra driving source pin

Applications

- DC/DC converter for EV/HEV
- On board charger (OBC)

Description

This N-channel Power MOSFET is based on the most innovative super-junction MDmesh DM9 technology, suitable for medium/high voltage MOSFETs featuring very low R_{DS(on)} per area coupled with a fast-recovery diode. The silicon-based DM9 technology benefits from a multi-drain manufacturing process which allows an enhanced device structure. The fast-recovery diode featuring very low recovery charge (Q_{rr}), time (t_{rr}) and R_{DS(on)} makes this fast-switching super-junction Power MOSFET tailored for the most demanding high-efficiency bridge topologies and ZVS phase-shift converters.

1 Electrical ratings

Table 1. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|---|------------|------------------|
| V_{GS} | Gate-source voltage | ± 30 | V |
| $I_D^{(1)}$ | Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$ | 51 | A |
| | Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$ | 32 | |
| $I_{DM}^{(2)}$ | Drain current (pulsed) | 220 | A |
| P_{TOT} | Total power dissipation at $T_C = 25\text{ }^\circ\text{C}$ | 245 | W |
| $dv/dt^{(3)}$ | Peak diode recovery voltage slope | 120 | V/ns |
| $di/dt^{(3)}$ | Peak diode recovery current slope | 1000 | A/ μs |
| $dv/dt^{(4)}$ | MOSFET dv/dt ruggedness | 120 | V/ns |
| T_{stg} | Storage temperature range | -55 to 150 | $^\circ\text{C}$ |
| T_J | Operating junction temperature range | | $^\circ\text{C}$ |

1. Referred to TO-247 long leads package.
2. Pulse width limited by safe operating area.
3. $I_{SD} \leq 25.5\text{ A}$, $V_{DS} (\text{peak}) < V_{(BR)DSS}$, $V_{DD} = 400\text{ V}$.
4. $V_{DS} (\text{peak}) < V_{(BR)DSS}$, $V_{DD} = 400\text{ V}$.

Table 2. Thermal data

| Symbol | Parameter | Value | Unit |
|------------------|---|-------|--------------------|
| R_{thJC} | Thermal resistance, junction-to-case | 0.51 | $^\circ\text{C/W}$ |
| $R_{thJA}^{(1)}$ | Thermal resistance, junction-to-ambient | 30 | $^\circ\text{C/W}$ |

1. When mounted on a standard 1 inch² area of FR-4 PCB with 2-oz copper.

Table 3. Avalanche characteristics

| Symbol | Parameter | Value | Unit |
|----------|--|-------|------|
| I_{AR} | Avalanche current, repetitive or not repetitive (pulse width limited by T_J max.) | 6 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_J = 25\text{ }^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$) | 760 | mJ |

2 Electrical characteristics

$T_C = 25\text{ }^\circ\text{C}$ unless otherwise specified.

Table 4. On/off-states

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|-----------------------------------|--|------|------|-----------|---------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage | $V_{GS} = 0\text{ V}$, $I_D = 1\text{ mA}$ | 650 | | | V |
| I_{DSS} | Zero gate voltage drain current | $V_{GS} = 0\text{ V}$, $V_{DS} = 650\text{ V}$ | | | 5 | μA |
| I_{GSS} | Gate-body leakage current | $V_{DS} = 0\text{ V}$, $V_{GS} = \pm 25\text{ V}$ | | | ± 100 | nA |
| $V_{GS(th)}$ | Gate threshold voltage | $V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$ | 3.5 | 4.0 | 4.5 | V |
| $R_{DS(on)}$ | Static drain-source on-resistance | $V_{GS} = 10\text{ V}$, $I_D = 25.5\text{ A}$ | | 38 | 50 | m Ω |

Table 5. Dynamic characteristics

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------------------|-------------------------------|--|------|------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 400\text{ V}$, $f = 250\text{ kHz}$, $V_{GS} = 0\text{ V}$ | - | 4680 | - | pF |
| C_{oss} | Output capacitance | | - | 76 | - | pF |
| $C_{oss\text{ eq}}^{(1)}$ | Equivalent output capacitance | $V_{DS} = 0\text{ to }400\text{ V}$, $V_{GS} = 0\text{ V}$ | - | 1070 | - | pF |
| R_g | Intrinsic gate resistance | $f = 250\text{ kHz}$, open drain | - | 1 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 400\text{ V}$, $I_D = 25.5\text{ A}$, $V_{GS} = 0\text{ to }10\text{ V}$ (see Figure 14. Test circuit for gate charge behavior) | - | 100 | - | nC |
| Q_{gs} | Gate-source charge | | - | 26 | - | nC |
| Q_{gd} | Gate-drain charge | | - | 36 | - | nC |

1. $C_{oss\text{ eq}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to stated value.

Table 6. Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|--------------|---------------------|---|------|------|------|------|
| $t_{d(on)}$ | Turn-on delay time | $V_{DD} = 400\text{ V}$, $I_D = 25.5\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = 10\text{ V}$ | - | 29 | - | ns |
| t_r | Rise time | | - | 7 | - | ns |
| $t_{d(off)}$ | Turn-off delay time | (see Figure 13. Switching times test circuit for resistive load and Figure 18. Switching time waveform) | - | 80 | - | ns |
| t_f | Fall time | | - | 5 | - | ns |

Table 7. Source-drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|---|------|------|------|---------------|
| $I_{SD}^{(1)}$ | Source-drain current | | - | | 51 | A |
| $I_{SDM}^{(2)}$ | Source-drain current (pulsed) | | - | | 220 | A |
| $V_{SD}^{(3)}$ | Forward on voltage | $V_{GS} = 0\text{ V}$, $I_{SD} = 51\text{ A}$ | - | 1.1 | 1.6 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 51\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, | - | 170 | | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 150\text{ V}$ | - | 1.2 | | μC |
| I_{RRM} | Reverse recovery current | (see Figure 15. Test circuit for inductive load switching and diode recovery times) | - | 12 | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 51\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, | - | 225 | | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 150\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$ | - | 2.2 | | μC |
| I_{RRM} | Reverse recovery current | (see Figure 15. Test circuit for inductive load switching and diode recovery times) | - | 18 | | A |

1. Referred to TO-247 long leads package.
2. Pulse width is limited by safe operating area.
3. Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

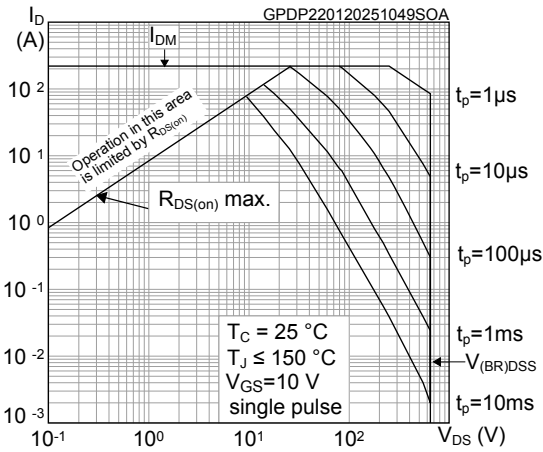


Figure 2. Maximum transient thermal impedance

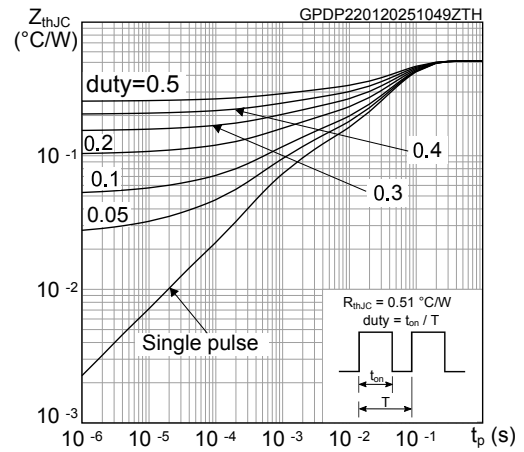


Figure 3. Typical output characteristics

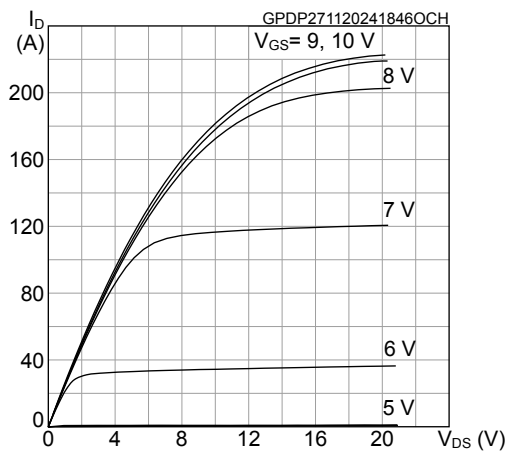


Figure 4. Typical transfer characteristics

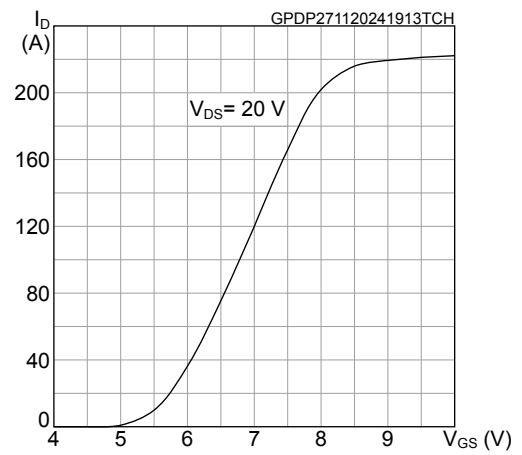


Figure 5. Typical gate charge characteristics

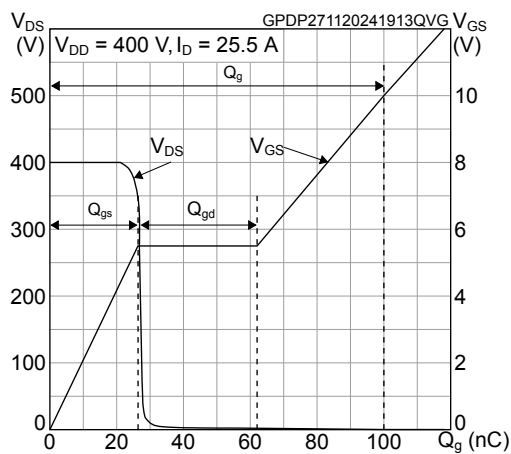


Figure 6. Typical capacitance characteristics

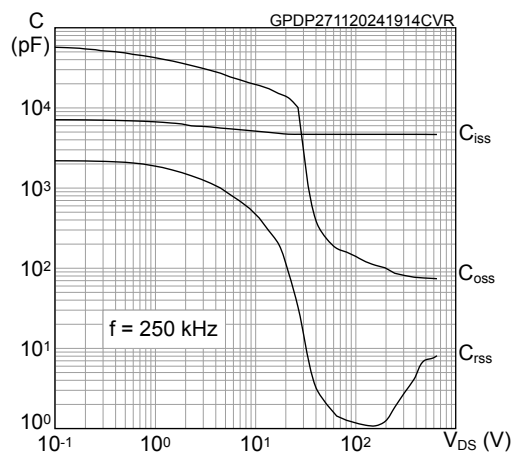


Figure 7. Typical drain-source on-resistance

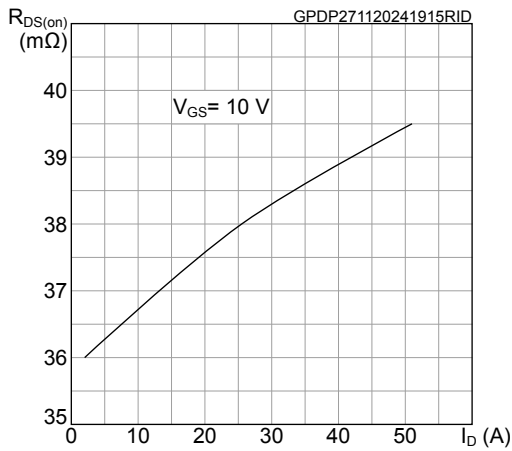


Figure 8. Normalized on-resistance vs temperature

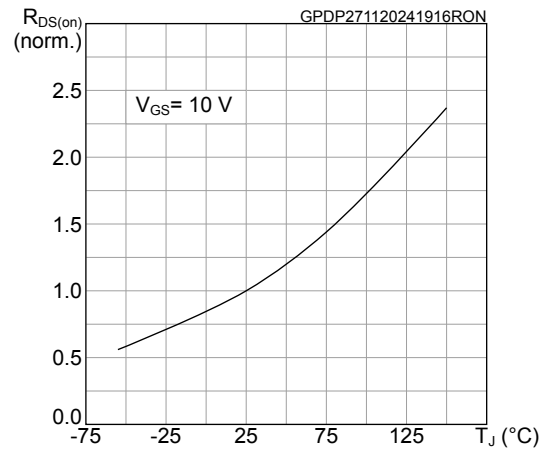


Figure 9. Normalized gate threshold vs temperature

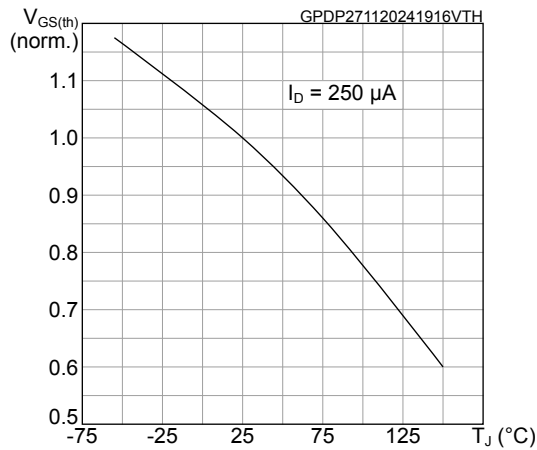


Figure 10. Normalized breakdown voltage vs temperature

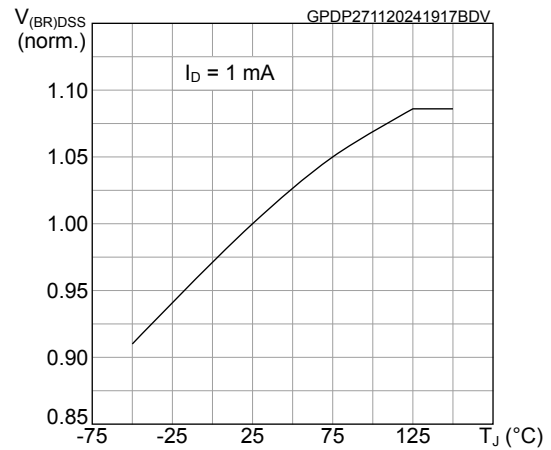


Figure 11. Typical reverse diode forward characteristics

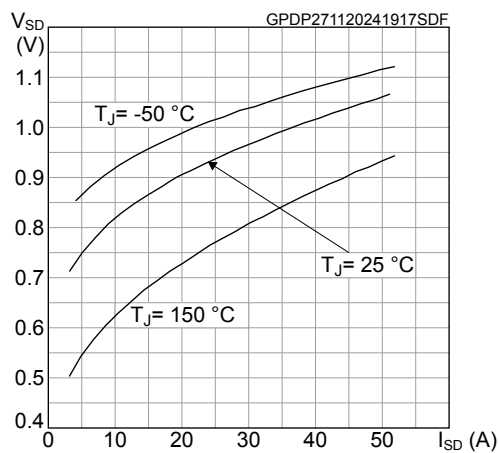
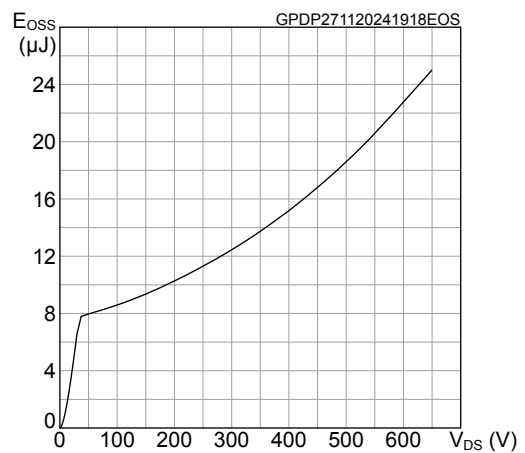
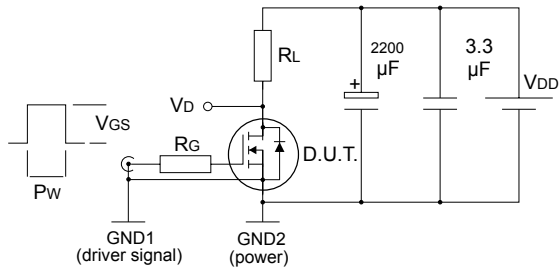


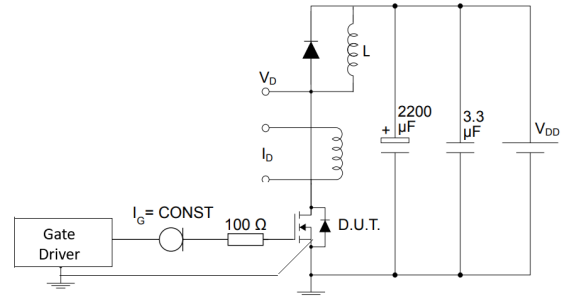
Figure 12. Typical output capacitance stored energy



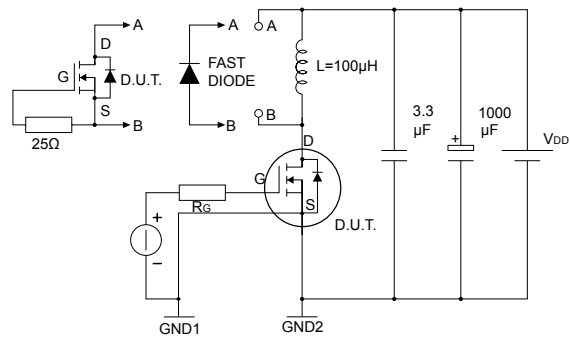
3 Test circuits

Figure 13. Switching times test circuit for resistive load


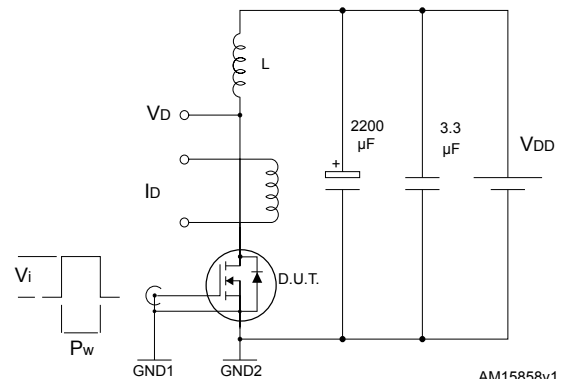
AM15855v1

Figure 14. Test circuit for gate charge behavior


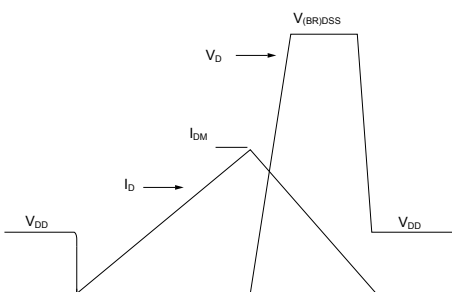
GPD191120241113SA

Figure 15. Test circuit for inductive load switching and diode recovery times


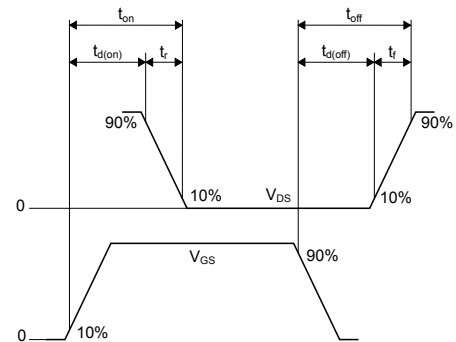
AM15857v1

Figure 16. Unclamped inductive load test circuit


AM15858v1

Figure 17. Unclamped inductive waveform


AM01472v1

Figure 18. Switching time waveform


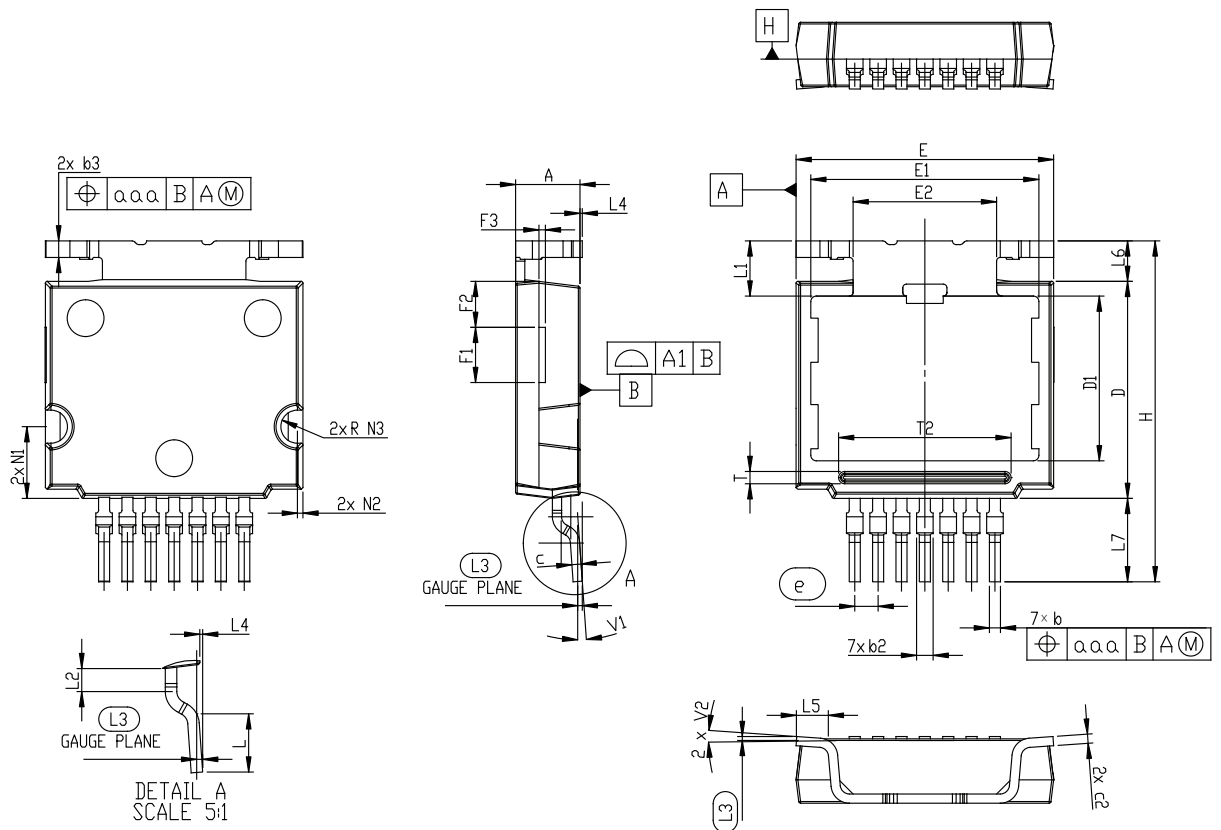
AM01473v1

4 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 HU3PAK package information

Figure 19. HU3PAK package outline

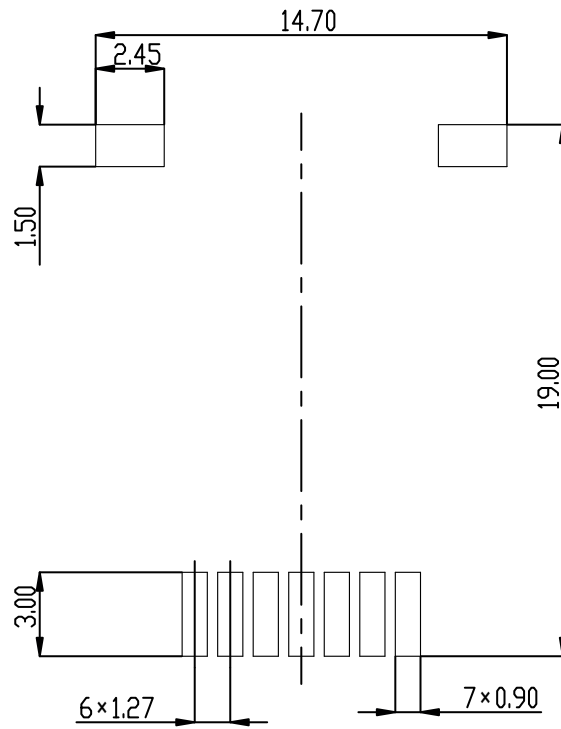


DM00674007_2

Table 8. HU3PAK package mechanical data

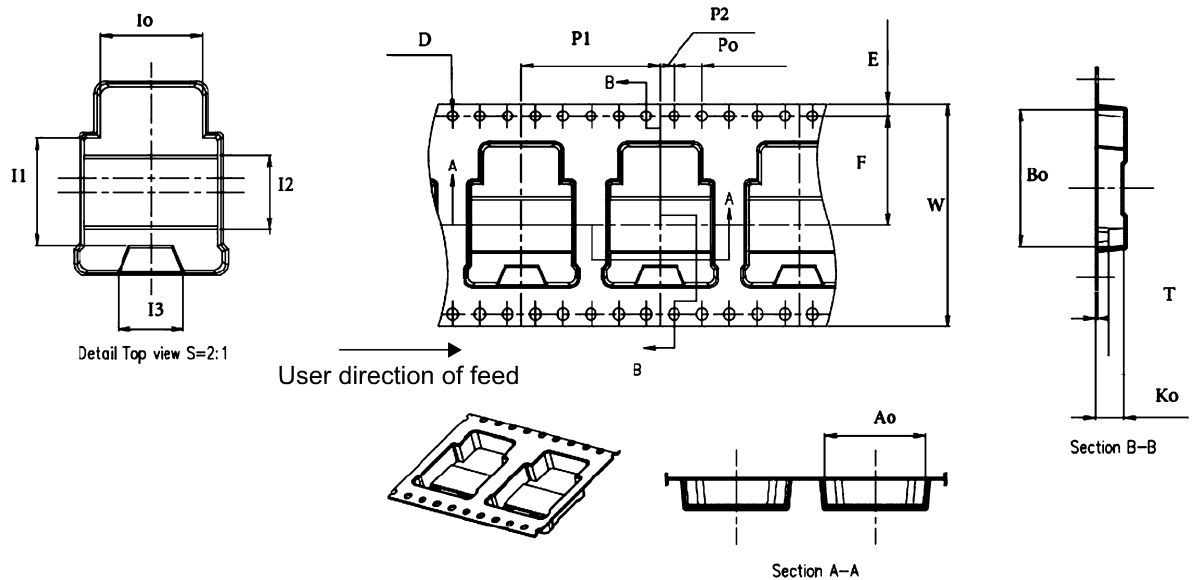
| Ref. | Dimensions | | |
|------|------------|-------|-------|
| | mm | | |
| | Min. | Typ. | Max. |
| A | 3.40 | 3.50 | 3.60 |
| A1 | | 0.05 | |
| b | 0.50 | 0.60 | 0.70 |
| b2 | 0.50 | 0.70 | 1.00 |
| b3 | 0.80 | 0.90 | 1.00 |
| c | 0.40 | 0.50 | 0.60 |
| c2 | 0.40 | 0.50 | 0.60 |
| D | 11.70 | 11.80 | 11.90 |
| D1 | 8.80 | 8.955 | 9.10 |
| E | 13.90 | 14.00 | 14.10 |
| E1 | 12.30 | 12.40 | 12.50 |
| E2 | 7.75 | 7.80 | 7.85 |
| e | | 1.27 | |
| H | 18.00 | 18.58 | 19.00 |
| aaa | | 0.10 | |
| L | 2.40 | 2.52 | 2.60 |
| L1 | | 3.05 | |
| L2 | 0.90 | 1.00 | 1.10 |
| L3 | | 0.26 | |
| L4 | 0.075 | 0.125 | 0.175 |
| L5 | 1.83 | 1.93 | 2.03 |
| L6 | 2.14 | 2.24 | 2.34 |
| L7 | 4.44 | 4.54 | 4.64 |
| F1 | 2.90 | 3.00 | 3.10 |
| F2 | 2.40 | 2.50 | 2.60 |
| F3 | 0.25 | 0.35 | 0.45 |
| N1 | 3.80 | 3.90 | 4.00 |
| N2 | 0.25 | 0.30 | 0.45 |
| N3 | 0.80 | 0.90 | 1.00 |
| T | 0.50 | 0.67 | 0.70 |
| T2 | 9.18 | 9.38 | 9.43 |
| V1 | | 0° | 8° |
| V2 | | 0° | 8° |

Figure 20. HU3PAK recommended footprint (dimensions in mm)



4.2 HU3PAK packing information

Figure 21. HU3PAK carrier tape outline



DM00345054_3

Revision history

Table 10. Document revision history

| Date | Revision | Changes |
|-------------|----------|--|
| 18-Jun-2024 | 1 | First release. |
| 23-Jan-2025 | 2 | Updated <i>Features</i> . Updated <i>Table 1. Absolute maximum ratings</i> and added <i>Table 3. Avalanche characteristics</i> . Updated <i>Section 2: Electrical characteristics</i> . Updated <i>Section 2.1: Electrical characteristics (curves)</i> . |
| 10-Feb-2025 | 3 | Updated Section Applications . |

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